

# FQD3P50 P-Channel QFET<sup>®</sup> MOSFET - 500 V, - 2.1 A, 4.9 Ω

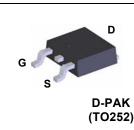
### Description

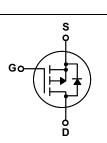
This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

### July 2013

### Features

- + 2.1 A, 500 V,  ${\sf R}_{\sf DS(on)}$  = 4.9  $\Omega$  (Max.) @  ${\sf V}_{\sf GS}$  = 10 V, ID = 1.05 A
- Low Gate Charge (Typ. 18 nC)
- Low Crss (Typ. 9.5 pF)
- 100% Avalanche Tested





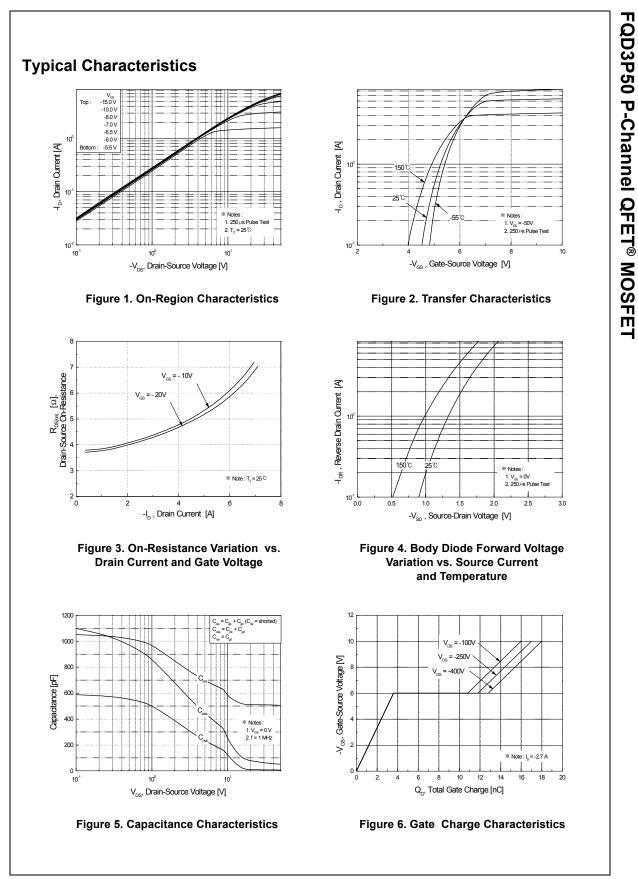
### Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQD3P50	Unit
V <sub>DSS</sub>	Drain-Source Voltage		-500	V
I <sub>D</sub>	Drain Current - Continuous ( $T_C = 25^{\circ}C$ )		-2.1	А
	- Continuous (T <sub>C</sub> = 100°C)		-1.33	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-8.4	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-2.1	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
Τ <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

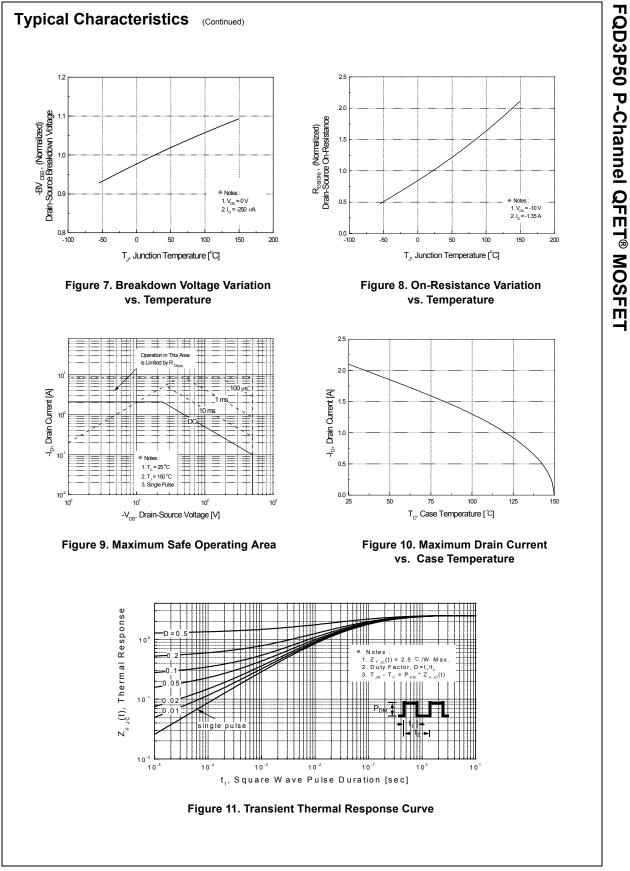
Symbol	Parameter	FQD3P50	Unit	
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction-to-Case, Max.	2.5	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max. *	50	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	110	°C/W	

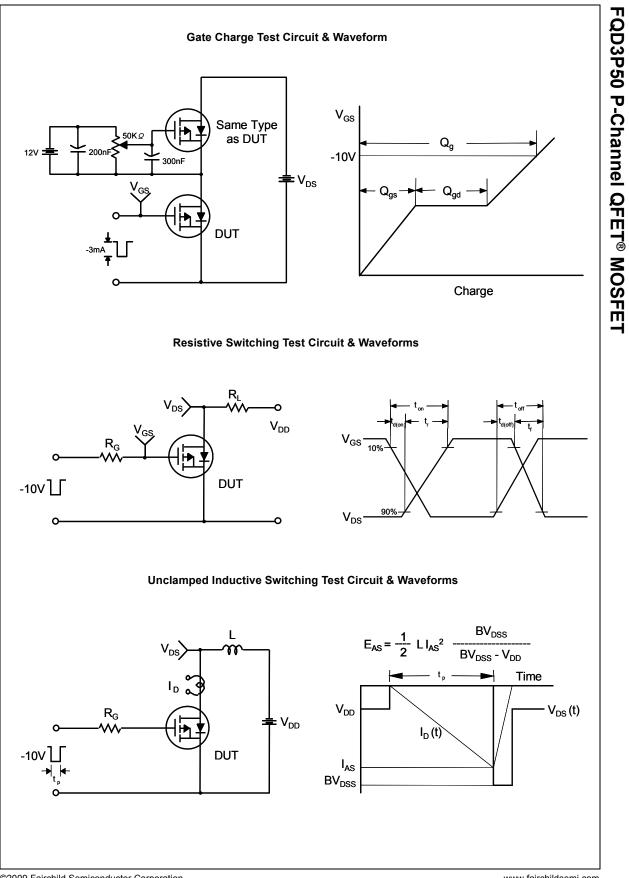
cteristics rain-Source Breakdown Voltage reakdown Voltage Temperature oefficient ero Gate Voltage Drain Current ate-Body Leakage Current, Forward ate-Body Leakage Current, Reverse cteristics ate Threshold Voltage tatic Drain-Source n-Resistance	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$ $I_{D} = -250 \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -500 \text{V}, \text{V}_{GS} = 0 \text{V}$ $V_{DS} = -400 \text{V}, \text{T}_{C} = 125^{\circ}\text{C}$ $V_{GS} = -30 \text{V}, \text{V}_{DS} = 0 \text{V}$ $V_{GS} = 30 \text{V}, \text{V}_{DS} = 0 \text{V}$ $V_{GS} = 30 \text{V}, \text{V}_{DS} = 0 \text{V}$ $V_{DS} = V_{GS}, \text{I}_{D} = -250 \mu\text{A}$	-500     	 0.42    	  -1 -10 -100 100	V V/°C μA μA nA
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ate-Body Leakage Current, Forward ate-Body Leakage Current, Reverse cteristics ate Threshold Voltage tatic Drain-Source	$V_{DS} = -400 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$ $V_{GS} = -30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ $V_{GS} = 30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			-10 -100	μA nA
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ate-Body Leakage Current, Reverse cteristics ate Threshold Voltage tatic Drain-Source	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V				
cteristics ate Threshold Voltage tatic Drain-Source				100	nA
ate Threshold Voltage tatic Drain-Source	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA				101
tatic Drain-Source	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$				
		-3.0		-5.0	V
	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.05 A		3.9	4.9	Ω
orward Transconductance	V <sub>DS</sub> = -50 V, I <sub>D</sub> = -1.05 A		2.1		S
Characteristics					
			510	660	pF
			70	90	pF
• •			-		pF
urn-On Delay Time urn-On Rise Time	$V_{DD} = -250 \text{ V}, \text{ I}_{D} = -2.7 \text{ A},$		12 56	35 120	ns ns
urn-On Rise Time			56	120	ns
urn-Off Delay Time			35	80	ns
urn-Off Fall Time	(Note 4)		45	100	ns
otal Gate Charge	V <sub>DS</sub> = -400 V, I <sub>D</sub> = -2.7 A,		18	23	nC
ate-Source Charge	V <sub>GS</sub> = -10 V		3.6		nC
ate-Drain Charge	(Note 4)		9.2		nC
urca Diada Charactoristics ar	nd Maximum Patings				
	•			-2.1	Α
aximum Pulsed Drain-Source Diode F	orward Current			-8.4	Α
rain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.1 A			-5.0	V
everse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.7 A,		270		ns
	urn-On Rise Time urn-Off Delay Time urn-Off Fall Time otal Gate Charge ate-Source Charge ate-Drain Charge rce Diode Characteristics ar aximum Continuous Drain-Source Dio	put Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ utput Capacitancef = 1.0 MHzeverse Transfer Capacitancef = 1.0 MHzCharacteristicsurn-On Delay Time $V_{DD} = -250 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ urn-On Rise Time $R_G = 25 \Omega$ urn-Off Delay Time $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ urn-Off Fall Time $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ utal Gate Charge $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ utal Gate Charge $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ utal Gate Charge $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ utal David Observe $V_{DS} = -10 \text{ V}$	put Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHzutput Capacitancef = 1.0 MHzcharacteristicsurn-On Delay Timeurn-On Rise Time $V_{DD} = -250 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ urn-Off Delay Time $V_{DS} = -250 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ urn-Off Fall Time $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ urn-Off Fall Time $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ tal Gate Charge $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ $V_{GS} = -10 \text{ V}$ trace Diode Characteristics and Maximum Ratingsaximum Continuous Drain-Source Diode Forward Current	put Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz510utput Capacitancef = 1.0 MHz70everse Transfer Capacitance9.5Characteristicsurn-On Delay Time $V_{DD} = -250 \text{ V}, I_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ 12urn-Off Delay Time $V_{DS} = -250 \text{ V}, I_D = -2.7 \text{ A},$ $R_G = 25 \Omega$ 12urn-Off Fall Time $(Note 4)$ 45utal Gate Charge $V_{DS} = -400 \text{ V}, I_D = -2.7 \text{ A},$ $M_{GS} = -10 \text{ V}$ 18ute-Drain Charge $V_{GS} = -10 \text{ V}$ 3.6ate-Drain Charge $(Note 4)$ 9.2rce Diode Characteristics and Maximum Ratingsaximum Continuous Drain-Source Diode Forward Current	put Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ 510         660           utput Capacitance         f = 1.0 MHz          70         90           everse Transfer Capacitance         f = 1.0 MHz          9.5         12           Characteristics         urn-On Delay Time $V_{DD} = -250 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ 12         35           urn-On Rise Time $V_{DD} = -250 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ 56         120           urn-Off Delay Time $V_{CS} = 25 \Omega$ (Note 4)          45         100           urn-Off Fall Time $V_{DS} = -400 \text{ V}, \text{ I}_D = -2.7 \text{ A},$ 18         23           ate-Source Charge $V_{GS} = -10 \text{ V}$ 18         23           ate-Source Charge $V_{GS} = -10 \text{ V}$ 9.2            rce Diode Characteristics and Maximum Ratings           -2.1



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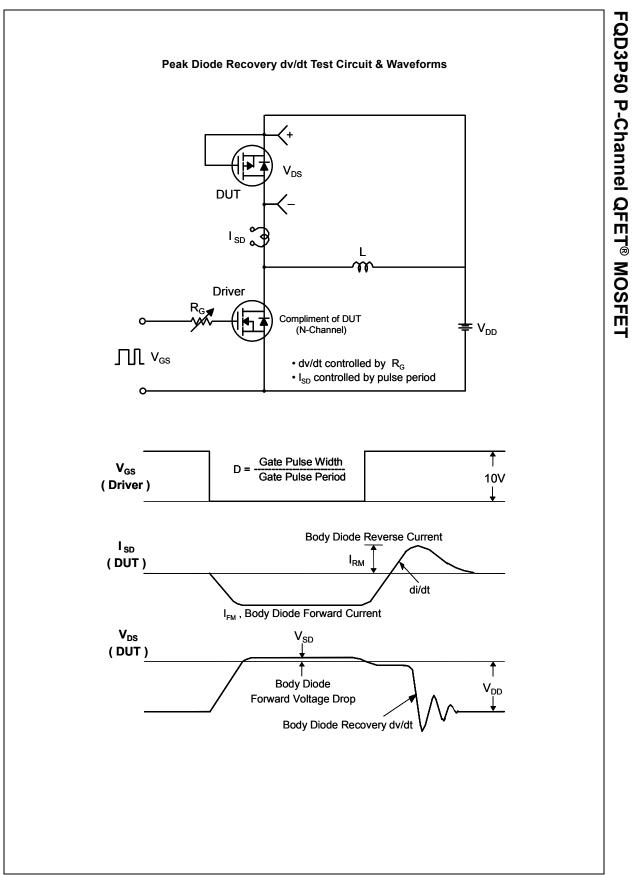
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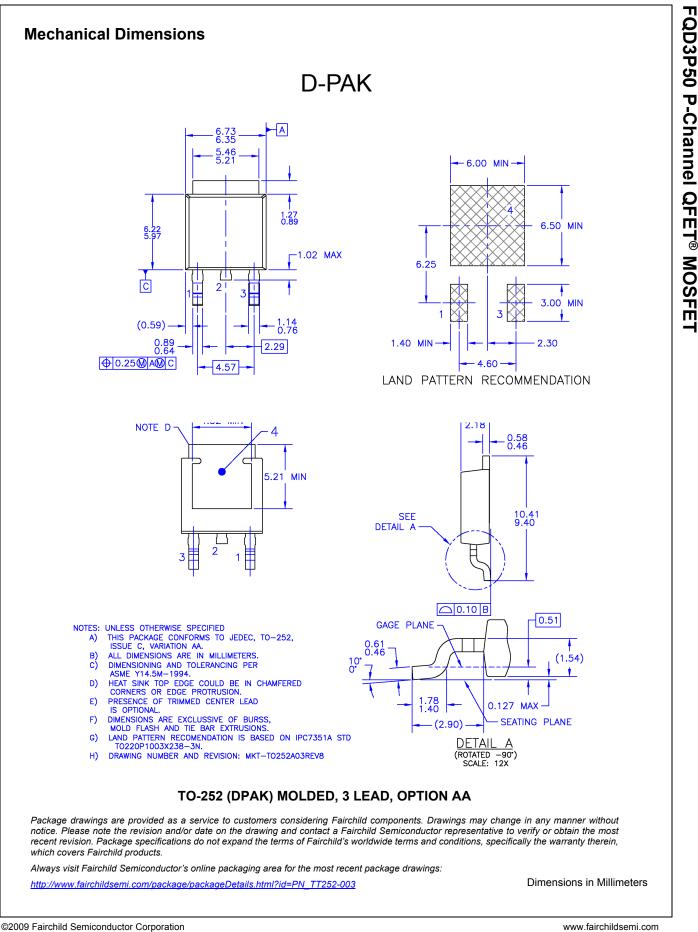




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